

**Notice of References Cited**

Application/Control No.

10/517,925

Applicant(s)/Patent Under  
Reexamination  
IMMINK ET AL.

Examiner

Henok G. Heyi

Art Unit

2609

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,208,799 A	05-1993	Nakao et al.	369/13.03
*	B	US-5,793,712 A	08-1998	Nishimura et al.	369/13.05
*	C	US-5,883,863 A	03-1999	Itakura et al.	369/13.05
*	D	US-6,058,077 A	05-2000	Miyaoka, Yasuyuki	369/13.24
*	E	US-6,246,641 B1	06-2001	Miyaoka, Yasuyuki	369/13.05
*	F	US-2003/0179657 A1	09-2003	Noguchi et al.	369/13.05
*	G	US-6,646,968 B1	11-2003	Miyaoka, Yasuyuki	369/53.31
*	H	US-2003/0227831 A1	12-2003	Herget, Philipp	369/13.05
*	I	US-6,693,854 B2	02-2004	Shimazaki et al.	369/13.05
*	J	US-6,801,478 B1	10-2004	Nishimoto, Hideki	369/13.14
*	K	US-7,200,072 B2	04-2007	Arisaka, Katsumi	369/13.05
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 913818 A1	05-1999	European Patent	OONUKEI et al.	G11B 11/10
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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